Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/086,262	CHANG ET AL.	
Examiner	Art Unit	
Steven HD Nauven	2665	

	SEARCHED .			
Class	Subclass	Date	Examiner	
370	351-356, 401	1/31/2006	ST	
379	265.02			
	88.17			
	900			
	142.07			
	210.01	•		
	225, 231			
	265.09	:		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			
See Fa	xt	5/3/67	8	
1	T .	5/3/67	9	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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